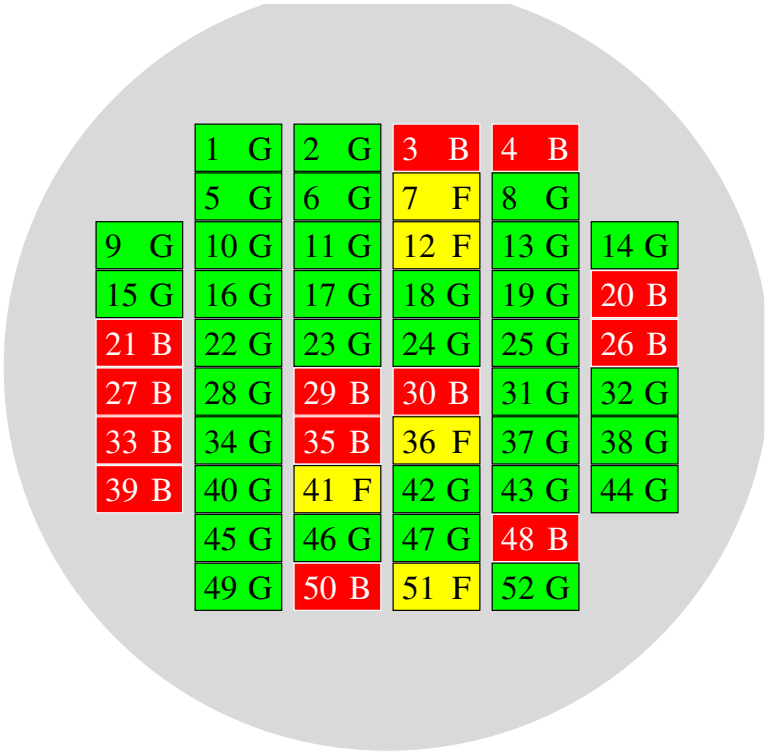
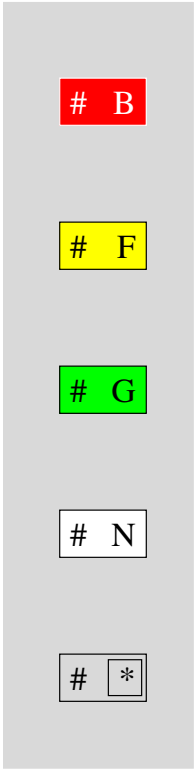
Die quality map for wafer 124 s/n: 21316-04-15

Date: 02/26/99